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What is "[Embedded - Microcontrollers](#)"?

"[Embedded - Microcontrollers](#)" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

Applications of "[Embedded - Microcontrollers](#)"

Details

Product Status	Active
Core Processor	ARM® Cortex®-M4
Core Size	32-Bit Single-Core
Speed	84MHz
Connectivity	I ² C, IrDA, LINbus, SDIO, SPI, UART/USART, USB OTG
Peripherals	Brown-out Detect/Reset, DMA, I ² S, POR, PWM, WDT
Number of I/O	36
Program Memory Size	512KB (512K x 8)
Program Memory Type	FLASH
EEPROM Size	-
RAM Size	96K x 8
Voltage - Supply (Vcc/Vdd)	1.7V ~ 3.6V
Data Converters	A/D 10x12b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 85°C (TA)
Mounting Type	Surface Mount
Package / Case	49-UFBGA, WLCSP
Supplier Device Package	49-WLCSP
Purchase URL	https://www.e-xfl.com/product-detail/stmicroelectronics/stm32f401cey6tr

6.3.6	Supply current characteristics	65
6.3.7	Wakeup time from low-power modes	75
6.3.8	External clock source characteristics	76
6.3.9	Internal clock source characteristics	80
6.3.10	PLL characteristics	82
6.3.11	PLL spread spectrum clock generation (SSCG) characteristics	84
6.3.12	Memory characteristics	85
6.3.13	EMC characteristics	87
6.3.14	Absolute maximum ratings (electrical sensitivity)	89
6.3.15	I/O current injection characteristics	90
6.3.16	I/O port characteristics	91
6.3.17	NRST pin characteristics	96
6.3.18	TIM timer characteristics	97
6.3.19	Communications interfaces	98
6.3.20	12-bit ADC characteristics	106
6.3.21	Temperature sensor characteristics	112
6.3.22	V _{BAT} monitoring characteristics	112
6.3.23	Embedded reference voltage	112
6.3.24	SD/SDIO MMC card host interface (SDIO) characteristics	113
6.3.25	RTC characteristics	114
7	Package characteristics	115
7.1	Package mechanical data	115
7.1.1	WLCSP49, 3.06 x 3.06 mm, 0.4 mm pitch wafer level chip size package	116
7.1.2	UFQFPN48, 7 x 7 mm, 0.5 mm pitch package	119
7.1.3	LQFP64, 10 x 10 mm, 64-pin low-profile quad flat package	122
7.1.4	LQFP100, 14 x 14 mm, 100-pin low-profile quad flat package	125
7.1.5	UFBGA100, 7 x 7 mm, 0.5 mm pitch package	128
7.2	Thermal characteristics	131
7.2.1	Reference document	131
8	Part numbering	132
9	Revision history	134

List of tables

Table 1.	Device summary	1
Table 2.	STM32F401xD/xE features and peripheral counts	11
Table 3.	Regulator ON/OFF and internal power supply supervisor availability.	25
Table 4.	Timer feature comparison	27
Table 5.	Comparison of I2C analog and digital filters	29
Table 6.	USART feature comparison	30
Table 7.	Legend/abbreviations used in the pinout table	38
Table 8.	STM32F401xD/xE pin definitions	38
Table 9.	Alternate function mapping	45
Table 10.	STM32F401xD register boundary addresses	52
Table 11.	Voltage characteristics	58
Table 12.	Current characteristics	59
Table 13.	Thermal characteristics	59
Table 14.	General operating conditions	60
Table 15.	Features depending on the operating power supply range	61
Table 16.	VCAP1/VCAP2 operating conditions	62
Table 17.	Operating conditions at power-up / power-down (regulator ON)	63
Table 18.	Operating conditions at power-up / power-down (regulator OFF).	63
Table 19.	Embedded reset and power control block characteristics.	64
Table 20.	Typical and maximum current consumption, code with data processing (ART accelerator disabled) running from SRAM - $V_{DD} = 1.7\text{ V}$	66
Table 21.	Typical and maximum current consumption, code with data processing (ART accelerator disabled) running from SRAM	66
Table 22.	Typical and maximum current consumption in run mode, code with data processing (ART accelerator enabled except prefetch) running from Flash memory- $V_{DD} = 1.7\text{ V}$	67
Table 23.	Typical and maximum current consumption in run mode, code with data processing (ART accelerator enabled except prefetch) running from Flash memory - $V_{DD} = 3.3\text{ V}$	67
Table 24.	Typical and maximum current consumption in run mode, code with data processing (ART accelerator disabled) running from Flash memory	68
Table 25.	Typical and maximum current consumption in run mode, code with data processing (ART accelerator enabled with prefetch) running from Flash memory	68
Table 26.	Typical and maximum current consumption in Sleep mode	69
Table 27.	Typical and maximum current consumptions in Stop mode - $V_{DD}=1.8\text{ V}$	69
Table 28.	Typical and maximum current consumption in Stop mode - $V_{DD}=3.3\text{ V}$	70
Table 29.	Typical and maximum current consumption in Standby mode - $V_{DD}=1.8\text{ V}$	70
Table 30.	Typical and maximum current consumption in Standby mode - $V_{DD}=3.3\text{ V}$	70
Table 31.	Typical and maximum current consumptions in V_{BAT} mode.	71
Table 32.	Switching output I/O current consumption	73
Table 33.	Peripheral current consumption	74
Table 34.	Low-power mode wakeup timings ⁽¹⁾	75
Table 35.	High-speed external user clock characteristics.	76
Table 36.	Low-speed external user clock characteristics	77
Table 37.	HSE 4-26 MHz oscillator characteristics.	78
Table 38.	LSE oscillator characteristics ($f_{LSE} = 32.768\text{ kHz}$)	79
Table 39.	HSI oscillator characteristics	80
Table 40.	LSI oscillator characteristics	81
Table 41.	Main PLL characteristics.	82
Table 42.	PLL12S (audio PLL) characteristics	83

Table 43.	SSCG parameters constraint	84
Table 44.	Flash memory characteristics	85
Table 45.	Flash memory programming	86
Table 46.	Flash memory programming with V_{PP} voltage	86
Table 47.	Flash memory endurance and data retention	87
Table 48.	EMS characteristics for LQFP100 package	88
Table 49.	EMI characteristics for WLCSP49	89
Table 50.	EMI characteristics for LQFP100	89
Table 51.	ESD absolute maximum ratings	90
Table 52.	Electrical sensitivities	90
Table 53.	I/O current injection susceptibility	91
Table 54.	I/O static characteristics	91
Table 55.	Output voltage characteristics	94
Table 56.	I/O AC characteristics	94
Table 57.	NRST pin characteristics	96
Table 58.	TIMx characteristics	97
Table 59.	I ² C characteristics	98
Table 60.	SCL frequency (f_{PCLK1} = 42 MHz, V_{DD} = V_{DD_I2C} = 3.3 V)	99
Table 61.	SPI dynamic characteristics	100
Table 62.	I ² S dynamic characteristics	103
Table 63.	USB OTG FS startup time	105
Table 64.	USB OTG FS DC electrical characteristics	105
Table 65.	USB OTG FS electrical characteristics	106
Table 66.	ADC characteristics	106
Table 67.	ADC accuracy at f_{ADC} = 18 MHz	108
Table 68.	ADC accuracy at f_{ADC} = 30 MHz	108
Table 69.	ADC accuracy at f_{ADC} = 36 MHz	108
Table 70.	ADC dynamic accuracy at f_{ADC} = 18 MHz - limited test conditions	109
Table 71.	ADC dynamic accuracy at f_{ADC} = 36 MHz - limited test conditions	109
Table 72.	Temperature sensor characteristics	112
Table 73.	Temperature sensor calibration values	112
Table 74.	V_{BAT} monitoring characteristics	112
Table 75.	Embedded internal reference voltage	112
Table 76.	Internal reference voltage calibration values	113
Table 77.	Dynamic characteristics: SD / MMC characteristics	114
Table 78.	RTC characteristics	114
Table 79.	STM32F401xCE WLCSP49 wafer level chip size package mechanical data	116
Table 80.	WLCSP49 recommended PCB design rules (0.4 mm pitch)	118
Table 81.	UFQFPN48, 7 x 7 mm, 0.5 mm pitch, package mechanical data	119
Table 82.	LQFP64, 10 x 10 mm, 64-pin low-profile quad flat package mechanical data	123
Table 83.	LQFP100, 14 x 14 mm, 100-pin low-profile quad flat package mechanical data	126
Table 84.	UFBGA100, 7 x 7 mm, 0.50 mm pitch, ultra fine pitch ball grid array package mechanical data	128
Table 85.	Package thermal characteristics	131
Table 86.	Ordering information scheme	132
Table 87.	Device order codes	133
Table 88.	Document revision history	134

3 Functional overview

3.1 ARM[®] Cortex[®]-M4 with FPU core with embedded Flash and SRAM

The ARM[®] Cortex[®]-M4 with FPU processor is the latest generation of ARM processors for embedded systems. It was developed to provide a low-cost platform that meets the needs of MCU implementation, with a reduced pin count and low-power consumption, while delivering outstanding computational performance and an advanced response to interrupts.

The ARM[®] Cortex[®]-M4 with FPU 32-bit RISC processor features exceptional code-efficiency, delivering the high-performance expected from an ARM core in the memory size usually associated with 8- and 16-bit devices. The processor supports a set of DSP instructions which allow efficient signal processing and complex algorithm execution. Its single precision FPU (floating point unit) speeds up software development by using metalanguage development tools, while avoiding saturation.

The STM32F401xD/xE devices are compatible with all ARM tools and software.

[Figure 3](#) shows the general block diagram of the STM32F401xD/xE.

Note: Cortex[®]-M4 with FPU is binary compatible with Cortex[®]-M3.

3.2 Adaptive real-time memory accelerator (ART Accelerator[™])

The ART Accelerator[™] is a memory accelerator which is optimized for STM32 industry-standard ARM[®] Cortex[®]-M4 with FPU processors. It balances the inherent performance advantage of the ARM[®] Cortex[®]-M4 with FPU over Flash memory technologies, which normally requires the processor to wait for the Flash memory at higher frequencies.

To release the processor full 105 DMIPS performance at this frequency, the accelerator implements an instruction prefetch queue and branch cache, which increases program execution speed from the 128-bit Flash memory. Based on CoreMark benchmark, the performance achieved thanks to the ART accelerator is equivalent to 0 wait state program execution from Flash memory at a CPU frequency up to 84 MHz.

3.3 Memory protection unit

The memory protection unit (MPU) is used to manage the CPU accesses to memory to prevent one task to accidentally corrupt the memory or resources used by any other active task. This memory area is organized into up to 8 protected areas that can in turn be divided up into 8 subareas. The protection area sizes are between 32 bytes and the whole 4 gigabytes of addressable memory.

The MPU is especially helpful for applications where some critical or certified code has to be protected against the misbehavior of other tasks. It is usually managed by an RTOS (real-time operating system). If a program accesses a memory location that is prohibited by the MPU, the RTOS can detect it and take action. In an RTOS environment, the kernel can dynamically update the MPU area setting, based on the process to be executed.

The MPU is optional and can be bypassed for applications that do not need it.

3.9 Nested vectored interrupt controller (NVIC)

The devices embed a nested vectored interrupt controller able to manage 16 priority levels, and handle up to 62 maskable interrupt channels plus the 16 interrupt lines of the Cortex[®]-M4 with FPU.

- Closely coupled NVIC gives low-latency interrupt processing
- Interrupt entry vector table address passed directly to the core
- Allows early processing of interrupts
- Processing of late arriving, higher-priority interrupts
- Support tail chaining
- Processor state automatically saved
- Interrupt entry restored on interrupt exit with no instruction overhead

This hardware block provides flexible interrupt management features with minimum interrupt latency.

3.10 External interrupt/event controller (EXTI)

The external interrupt/event controller consists of 21 edge-detector lines used to generate interrupt/event requests. Each line can be independently configured to select the trigger event (rising edge, falling edge, both) and can be masked independently. A pending register maintains the status of the interrupt requests. The EXTI can detect an external line with a pulse width shorter than the Internal APB2 clock period. Up to 81 GPIOs can be connected to the 16 external interrupt lines.

3.11 Clocks and startup

On reset the 16 MHz internal RC oscillator is selected as the default CPU clock. The 16 MHz internal RC oscillator is factory-trimmed to offer 1% accuracy at 25 °C. The application can then select as system clock either the RC oscillator or an external 4-26 MHz clock source. This clock can be monitored for failure. If a failure is detected, the system automatically switches back to the internal RC oscillator and a software interrupt is generated (if enabled). This clock source is input to a PLL thus allowing to increase the frequency up to 84 MHz. Similarly, full interrupt management of the PLL clock entry is available when necessary (for example if an indirectly used external oscillator fails).

Several prescalers allow the configuration of the two AHB buses, the high-speed APB (APB2) and the low-speed APB (APB1) domains. The maximum frequency of the two AHB buses is 84 MHz while the maximum frequency of the high-speed APB domains is 84 MHz. The maximum allowed frequency of the low-speed APB domain is 42 MHz.

The devices embed a dedicated PLL (PLL12S) which allows to achieve audio class performance. In this case, the I²S master clock can generate all standard sampling frequencies from 8 kHz to 192 kHz.

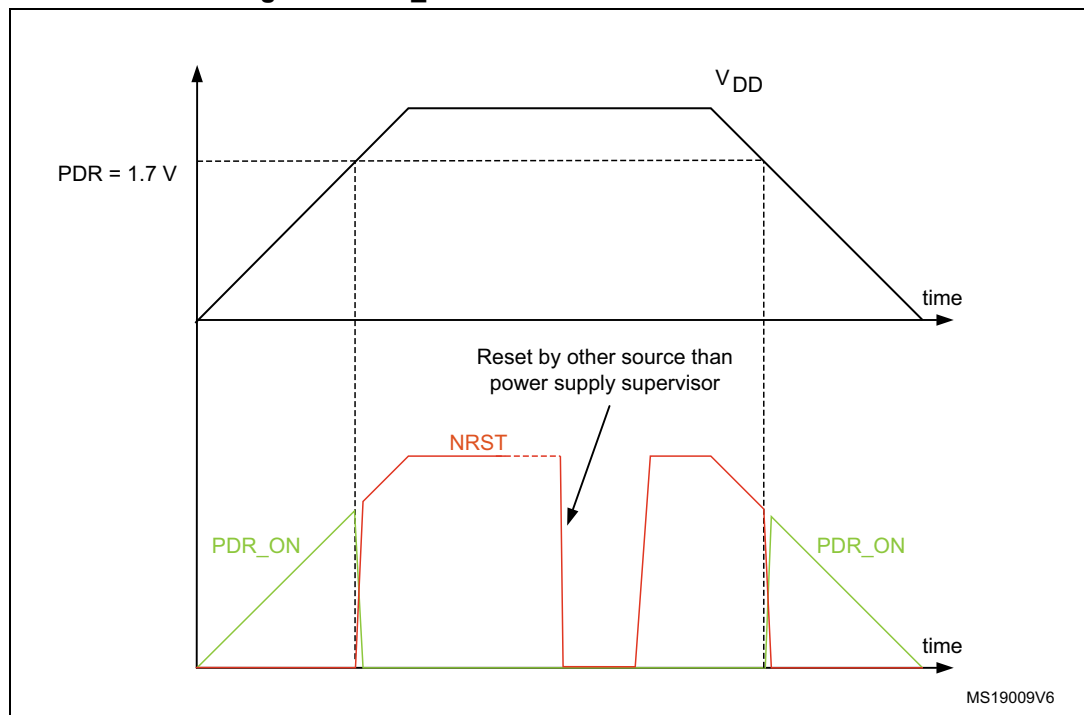
The V_{DD} specified threshold, below which the device must be maintained under reset, is 1.7 V (see [Figure 6](#)).

A comprehensive set of power-saving mode allows to design low-power applications.

When the internal reset is OFF, the following integrated features are no longer supported:

- The integrated power-on reset (POR) / power-down reset (PDR) circuitry is disabled.
- The brownout reset (BOR) circuitry must be disabled.
- The embedded programmable voltage detector (PVD) is disabled.
- V_{BAT} functionality is no more available and VBAT pin should be connected to V_{DD} .

Figure 6. PDR_ON control with internal reset OFF



3.15 Voltage regulator

The regulator has four operating modes:

- Regulator ON
 - Main regulator mode (MR)
 - Low power regulator (LPR)
 - Power-down
- Regulator OFF

3.15.1 Regulator ON

On packages embedding the BYPASS_REG pin, the regulator is enabled by holding BYPASS_REG low. On all other packages, the regulator is always enabled.

If configured as standard 16-bit timers, it has the same features as the general-purpose TIMx timers. If configured as a 16-bit PWM generator, it has full modulation capability (0-100%).

The advanced-control timer can work together with the TIMx timers via the Timer Link feature for synchronization or event chaining.

TIM1 supports independent DMA request generation.

3.19.2 General-purpose timers (TIMx)

There are seven synchronizable general-purpose timers embedded in the STM32F401xD/xE (see [Table 4](#) for differences).

- **TIM2, TIM3, TIM4, TIM5**

The STM32F401xD/xE devices are 4 full-featured general-purpose timers: TIM2, TIM5, TIM3, and TIM4. The TIM2 and TIM5 timers are based on a 32-bit auto-reload up/downcounter and a 16-bit prescaler. The TIM3 and TIM4 timers are based on a 16-bit auto-reload up/downcounter and a 16-bit prescaler. They all feature four independent channels for input capture/output compare, PWM or one-pulse mode output. This gives up to 15 input capture/output compare/PWMs.

The TIM2, TIM3, TIM4, TIM5 general-purpose timers can work together, or with the other general-purpose timers and the advanced-control timers TIM1 and TIM8 via the Timer Link feature for synchronization or event chaining.

Any of these general-purpose timers can be used to generate PWM outputs.

TIM2, TIM3, TIM4, TIM5 all have independent DMA request generation. They are capable of handling quadrature (incremental) encoder signals and the digital outputs from 1 to 4 hall-effect sensors.

- **TIM9, TIM10 and TIM11**

These timers are based on a 16-bit auto-reload upcounter and a 16-bit prescaler. TIM10 and TIM11 feature one independent channel, whereas TIM9 has two independent channels for input capture/output compare, PWM or one-pulse mode output. They can be synchronized with the TIM2, TIM3, TIM4, TIM5 full-featured general-purpose timers. They can also be used as simple time bases.

3.19.3 Independent watchdog

The independent watchdog is based on a 12-bit downcounter and 8-bit prescaler. It is clocked from an independent 32 kHz internal RC and as it operates independently from the main clock, it can operate in Stop and Standby modes. It can be used either as a watchdog to reset the device when a problem occurs, or as a free-running timer for application timeout management. It is hardware- or software-configurable through the option bytes.

3.19.4 Window watchdog

The window watchdog is based on a 7-bit downcounter that can be set as free-running. It can be used as a watchdog to reset the device when a problem occurs. It is clocked from the main clock. It has an early warning interrupt capability and the counter can be frozen in debug mode.

Table 6. USART feature comparison

USART name	Standard features	Modem (RTS/CTS)	LIN	SPI master	IrDA	Smartcard (ISO 7816)	Max. baud rate in Mbit/s (oversampling by 16)	Max. baud rate in Mbit/s (oversampling by 8)	APB mapping
USART1	X	X	X	X	X	X	5.25	10.5	APB2 (max. 84 MHz)
USART2	X	X	X	X	X	X	2.62	5.25	APB1 (max. 42 MHz)
USART6	X	N.A	X	X	X	X	5.25	10.5	APB2 (max. 84 MHz)

3.22 Serial peripheral interface (SPI)

The devices feature up to four SPIs in slave and master modes in full-duplex and simplex communication modes. SPI1 and SPI4 can communicate at up to 42 Mbit/s, SPI2 and SPI3 can communicate at up to 21 Mbit/s. The 3-bit prescaler gives 8 master mode frequencies and the frame is configurable to 8 bits or 16 bits. The hardware CRC generation/verification supports basic SD Card/MMC modes. All SPIs can be served by the DMA controller.

The SPI interface can be configured to operate in TI mode for communications in master mode and slave mode.

3.23 Inter-integrated sound (I²S)

Two standard I²S interfaces (multiplexed with SPI2 and SPI3) are available. They can be operated in master or slave mode, in full duplex and simplex communication modes and can be configured to operate with a 16-/32-bit resolution as an input or output channel. Audio sampling frequencies from 8 kHz up to 192 kHz are supported. When either or both of the I²S interfaces is/are configured in master mode, the master clock can be output to the external DAC/CODEC at 256 times the sampling frequency.

All I²Sx can be served by the DMA controller.

3.24 Audio PLL (PLL12S)

The devices feature an additional dedicated PLL for audio I²S application. It allows to achieve error-free I²S sampling clock accuracy without compromising on the CPU performance.

The PLL12S configuration can be modified to manage an I²S sample rate change without disabling the main PLL (PLL) used for the CPU.

The audio PLL can be programmed with very low error to obtain sampling rates ranging from 8 kHz to 192 kHz.

In addition to the audio PLL, a master clock input pin can be used to synchronize the I2S flow with an external PLL (or Codec output).

3.25 Secure digital input/output interface (SDIO)

An SD/SDIO/MMC host interface is available, that supports MultiMediaCard System Specification Version 4.2 in three different databus modes: 1-bit (default), 4-bit and 8-bit.

The interface allows data transfer at up to 48 MHz, and is compliant with the SD Memory Card Specification Version 2.0.

The SDIO Card Specification Version 2.0 is also supported with two different databus modes: 1-bit (default) and 4-bit.

The current version supports only one SD/SDIO/MMC4.2 card at any one time and a stack of MMC4.1 or previous.

In addition to SD/SDIO/MMC, this interface is fully compliant with the CE-ATA digital protocol Rev1.1.

3.26 Universal serial bus on-the-go full-speed (OTG_FS)

The devices embed an USB OTG full-speed device/host/OTG peripheral with integrated transceivers. The USB OTG FS peripheral is compliant with the USB 2.0 specification and with the OTG 1.0 specification. It has software-configurable endpoint setting and supports suspend/resume. The USB OTG full-speed controller requires a dedicated 48 MHz clock that is generated by a PLL connected to the HSE oscillator. The major features are:

- Combined Rx and Tx FIFO size of 320 × 35 bits with dynamic FIFO sizing
- Supports the session request protocol (SRP) and host negotiation protocol (HNP)
- 4 bidirectional endpoints
- 8 host channels with periodic OUT support
- HNP/SNP/IP inside (no need for any external resistor)
- For OTG/Host modes, a power switch is needed in case bus-powered devices are connected

3.27 General-purpose input/outputs (GPIOs)

Each of the GPIO pins can be configured by software as output (push-pull or open-drain, with or without pull-up or pull-down), as input (floating, with or without pull-up or pull-down) or as peripheral alternate function. Most of the GPIO pins are shared with digital or analog alternate functions. All GPIOs are high-current-capable and have speed selection to better manage internal noise, power consumption and electromagnetic emission.

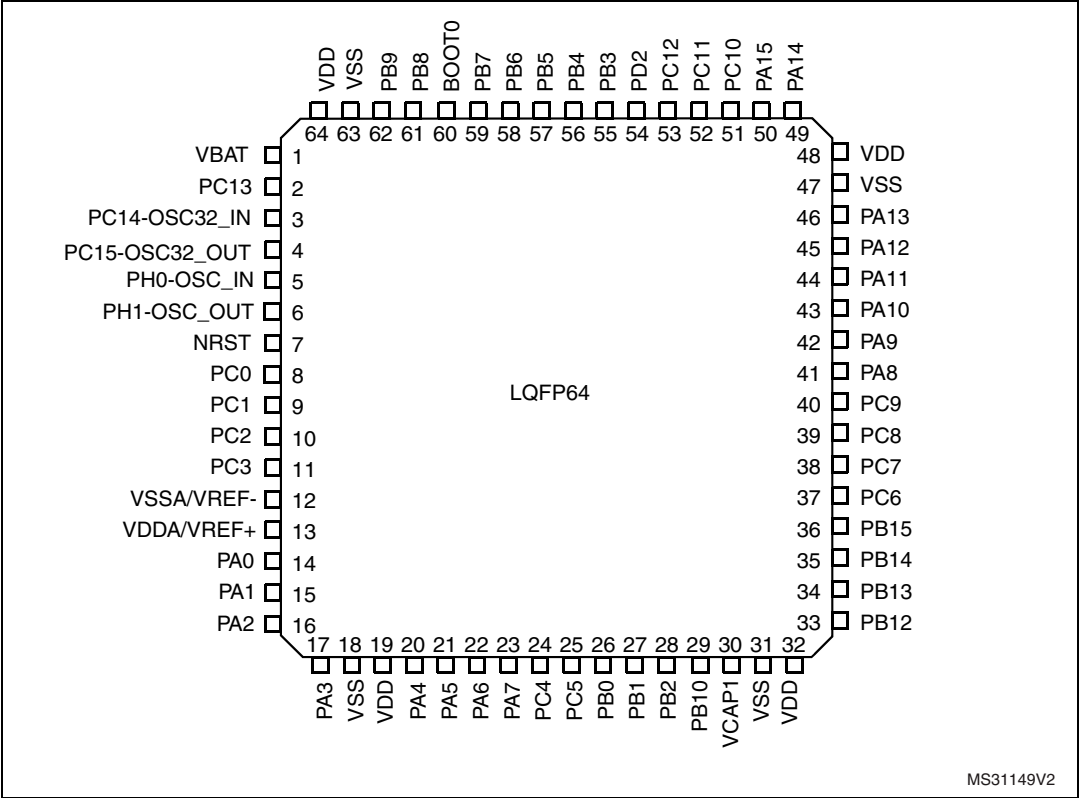
The I/O configuration can be locked if needed by following a specific sequence in order to avoid spurious writing to the I/Os registers.

Fast I/O handling allowing maximum I/O toggling up to 84 MHz.

3.28 Analog-to-digital converter (ADC)

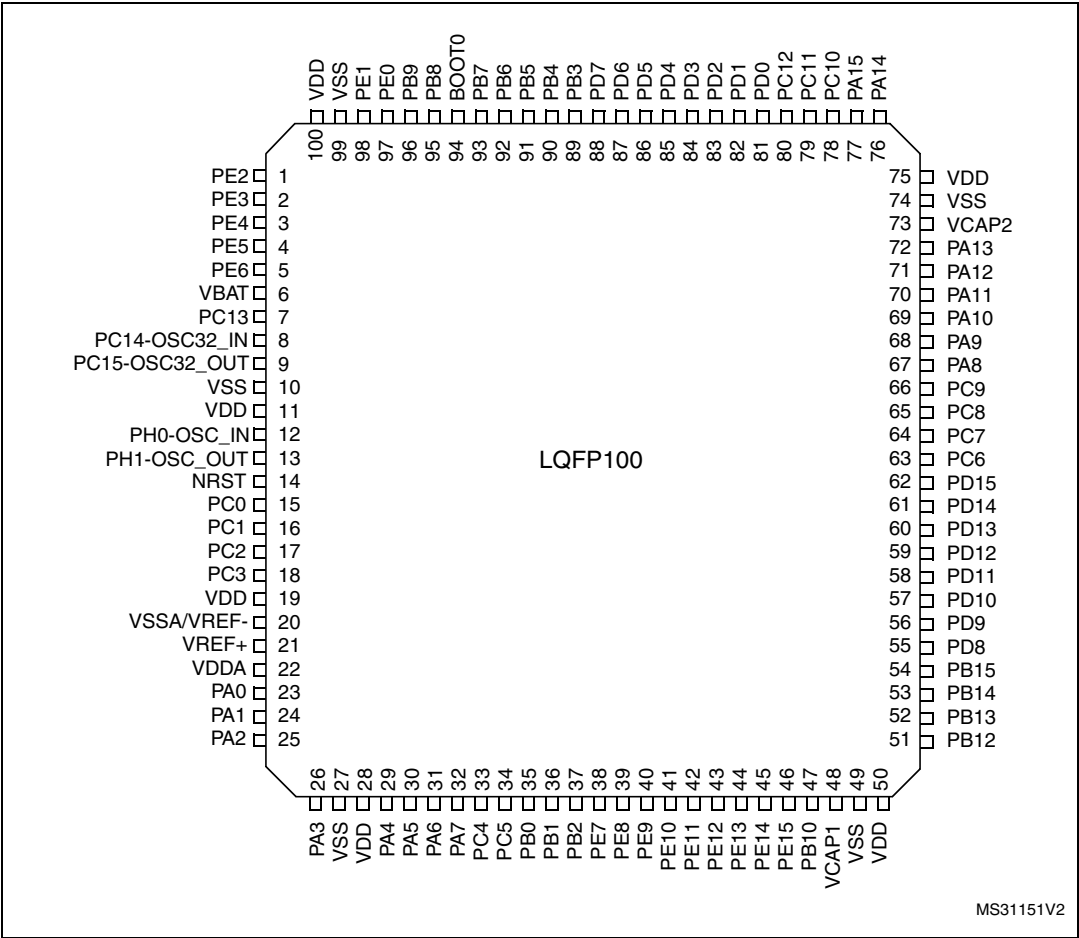
One 12-bit analog-to-digital converter is embedded and shares up to 16 external channels, performing conversions in the single-shot or scan mode. In scan mode, automatic conversion is performed on a selected group of analog inputs.

Figure 12. STM32F401xD/xE LQFP64 pinout



1. The above figure shows the package top view.

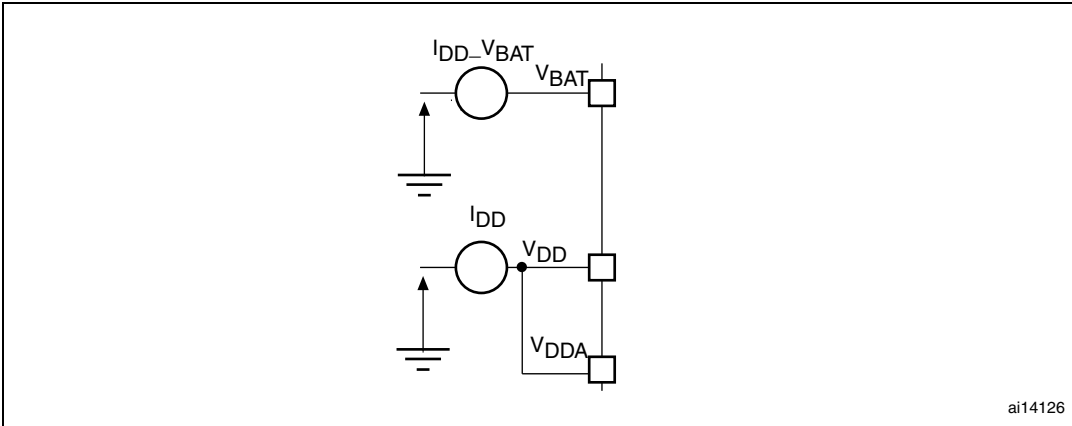
Figure 13. STM32F401xD/xE LQFP100 pinout



1. The above figure shows the package top view.

6.1.7 Current consumption measurement

Figure 19. Current consumption measurement scheme



6.2 Absolute maximum ratings

Stresses above the absolute maximum ratings listed in [Table 11: Voltage characteristics](#), [Table 12: Current characteristics](#), and [Table 13: Thermal characteristics](#) may cause permanent damage to the device. These are stress ratings only and functional operation of the device at these conditions is not implied. Exposure to maximum rating conditions for extended periods may affect device reliability.

Table 11. Voltage characteristics

Symbol	Ratings	Min	Max	Unit
$V_{DD}-V_{SS}$	External main supply voltage (including V_{DDA} , V_{DD} and V_{BAT}) ⁽¹⁾	-0.3	4.0	V
V_{IN}	Input voltage on FT pins ⁽²⁾	$V_{SS}-0.3$	$V_{DD}+4.0$	
	Input voltage on any other pin	$V_{SS}-0.3$	4.0	
	Input voltage for BOOT0	V_{SS}	9.0	mV
$ \Delta V_{DDx} $	Variations between different V_{DD} power pins	-	50	
$ V_{SSx}-V_{SS} $	Variations between all the different ground pins	-	50	
$V_{ESD(HBM)}$	Electrostatic discharge voltage (human body model)	see Section 6.3.14: Absolute maximum ratings (electrical sensitivity)		

1. All main power (V_{DD} , V_{DDA}) and ground (V_{SS} , V_{SSA}) pins must always be connected to the external power supply, in the permitted range.
2. V_{IN} maximum value must always be respected. Refer to [Table 12](#) for the values of the maximum allowed injected current.

Table 48. EMS characteristics for LQFP100 package

Symbol	Parameter	Conditions	Level/Class
V_{FESD}	Voltage limits to be applied on any I/O pin to induce a functional disturbance	$V_{DD} = 3.3\text{ V}$, LQFP100, WLCSP49, $T_A = +25\text{ }^{\circ}\text{C}$, $f_{HCLK} = 84\text{ MHz}$, conforms to IEC 61000-4-2	2B
V_{EFTB}	Fast transient voltage burst limits to be applied through 100 pF on V_{DD} and V_{SS} pins to induce a functional disturbance	$V_{DD} = 3.3\text{ V}$, LQFP100, WLCSP49, $T_A = +25\text{ }^{\circ}\text{C}$, $f_{HCLK} = 84\text{ MHz}$, conforms to IEC 61000-4-4	4A

When the application is exposed to a noisy environment, it is recommended to avoid pin exposition to disturbances. The pins showing a middle range robustness are: PA0, PA1, PA2, on LQFP100 packages and PDR_ON on WLCSP49.

As a consequence, it is recommended to add a serial resistor (1 k Ω maximum) located as close as possible to the MCU to the pins exposed to noise (connected to tracks longer than 50 mm on PCB).

Designing hardened software to avoid noise problems

EMC characterization and optimization are performed at component level with a typical application environment and simplified MCU software. It should be noted that good EMC performance is highly dependent on the user application and the software in particular.

Therefore it is recommended that the user applies EMC software optimization and prequalification tests in relation with the EMC level requested for his application.

Software recommendations

The software flowchart must include the management of runaway conditions such as:

- Corrupted program counter
- Unexpected reset
- Critical Data corruption (control registers...)

Prequalification trials

Most of the common failures (unexpected reset and program counter corruption) can be reproduced by manually forcing a low state on the NRST pin or the Oscillator pins for 1 second.

To complete these trials, ESD stress can be applied directly on the device, over the range of specification values. When unexpected behavior is detected, the software can be hardened to prevent unrecoverable errors occurring (see application note AN1015).

Table 53. I/O current injection susceptibility⁽¹⁾

Symbol	Description	Functional susceptibility		Unit
		Negative injection	Positive injection	
I_{INJ}	Injected current on BOOT0 pin	-0	NA	mA
	Injected current on NRST pin	-0	NA	
	Injected current on PB3, PB4, PB5, PB6, PB7, PB8, PB9, PC13, PC14, PC15, PH1, PDR_ON, PC0, PC1, PC2, PC3, PD1, PD5, PD6, PD7, PE0, PE2, PE3, PE4, PE5, PE6	-0	NA	
	Injected current on any other FT pin	-5	NA	
	Injected current on any other pins	-5	+5	

1. NA = not applicable.

Note: *It is recommended to add a Schottky diode (pin to ground) to analog pins which may potentially inject negative currents.*

6.3.16 I/O port characteristics

General input/output characteristics

Unless otherwise specified, the parameters given in [Table 54](#) are derived from tests performed under the conditions summarized in [Table 14](#). All I/Os are CMOS and TTL compliant.

Table 54. I/O static characteristics

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
V _{IL}	FT, and NRST I/O input low level voltage	1.7 V≤V _{DD} ≤3.6 V	-	-	0.35V _{DD} −0.04 ⁽¹⁾	V
					0.3V _{DD} ⁽²⁾	
	BOOT0 I/O input low level voltage	1.75 V≤V _{DD} ≤3.6 V, −40 °C≤T _A ≤105 °C	-	-	0.1V _{DD} +0.1	
		1.7 V≤V _{DD} ≤3.6 V, 0 °C≤T _A ≤105 °C	-	-		
V _{IH}	FT and NRST I/O input high level voltage ⁽⁵⁾	1.7 V≤V _{DD} ≤3.6 V	0.45V _{DD} +0.3 ⁽¹⁾	-	-	V
			0.4V _{DD} ⁽²⁾			
	BOOT0 I/O input high level voltage	1.75 V≤V _{DD} ≤3.6 V, −40 °C≤T _A ≤105 °C	0.17V _{DD} +0.7 ⁽¹⁾	-	-	
		1.7 V≤V _{DD} ≤3.6 V, 0 °C≤T _A ≤105 °C				

6.3.19 Communications interfaces

I²C interface characteristics

The I²C interface meets the requirements of the standard I²C communication protocol with the following restrictions: the I/O pins SDA and SCL are mapped to are not “true” open-drain. When configured as open-drain, the PMOS connected between the I/O pin and VDD is disabled, but is still present.

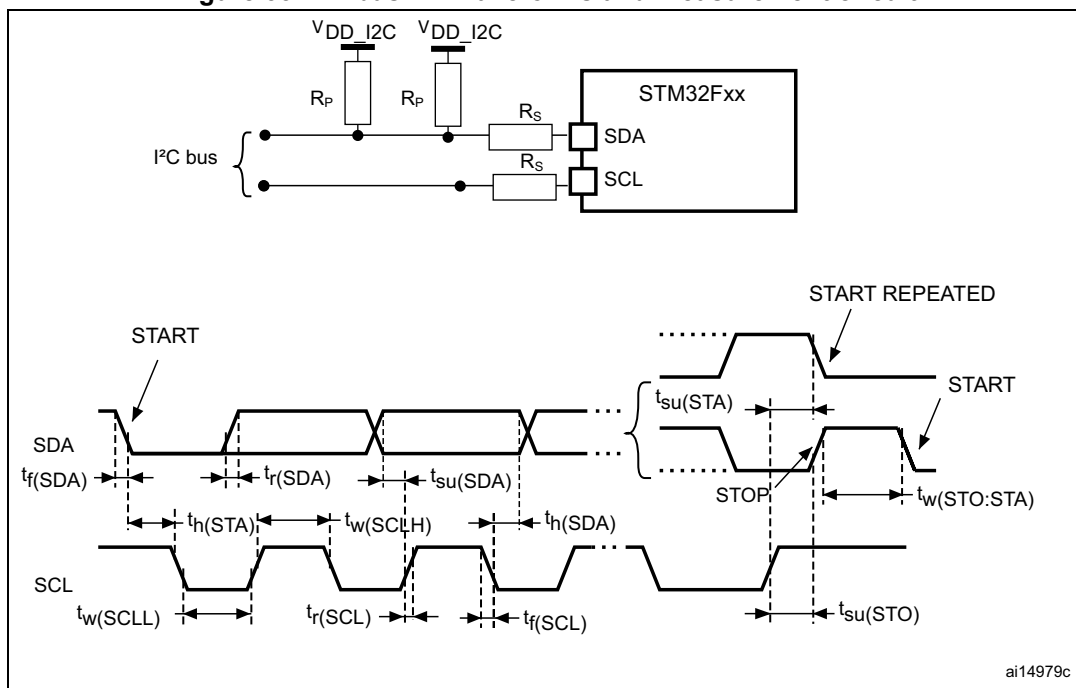
The I²C characteristics are described in [Table 59](#). Refer also to [Section 6.3.16: I/O port characteristics](#) for more details on the input/output alternate function characteristics (SDA and SCL).

The I²C bus interface supports standard mode (up to 100 kHz) and fast mode (up to 400 kHz). The I²C bus frequency can be increased up to 1 MHz. For more details about the complete solution, please contact your local ST sales representative.

Table 59. I²C characteristics

Symbol	Parameter	Standard mode I ² C ⁽¹⁾		Fast mode I ² C ⁽¹⁾⁽²⁾		Unit
		Min	Max	Min	Max	
t _w (SCLL)	SCL clock low time	4.7	-	1.3	-	μs
t _w (SCLH)	SCL clock high time	4.0	-	0.6	-	
t _{su} (SDA)	SDA setup time	250	-	100	-	ns
t _h (SDA)	SDA data hold time	0	-	0	900 ⁽³⁾	
t _r (SDA) t _r (SCL)	SDA and SCL rise time	-	1000		300	
t _f (SDA) t _f (SCL)	SDA and SCL fall time	-	300	-	300	
t _h (STA)	Start condition hold time	4.0	-	0.6	-	μs
t _{su} (STA)	Repeated Start condition setup time	4.7	-	0.6	-	
t _{su} (STO)	Stop condition setup time	4.0	-	0.6	-	μs
t _w (STO:STA)	Stop to Start condition time (bus free)	4.7	-	1.3	-	μs
C _b	Capacitive load for each bus line	-	400	-	400	pF

1. Guaranteed by design, not tested in production.
2. f_{CLK1} must be at least 2 MHz to achieve standard mode I²C frequencies. It must be at least 4 MHz to achieve fast mode I²C frequencies, and a multiple of 10 MHz to reach the 400 kHz maximum I²C fast mode clock.
3. The maximum data hold time has only to be met if the interface does not stretch the low period of SCL signal.

Figure 33. I²C bus AC waveforms and measurement circuit

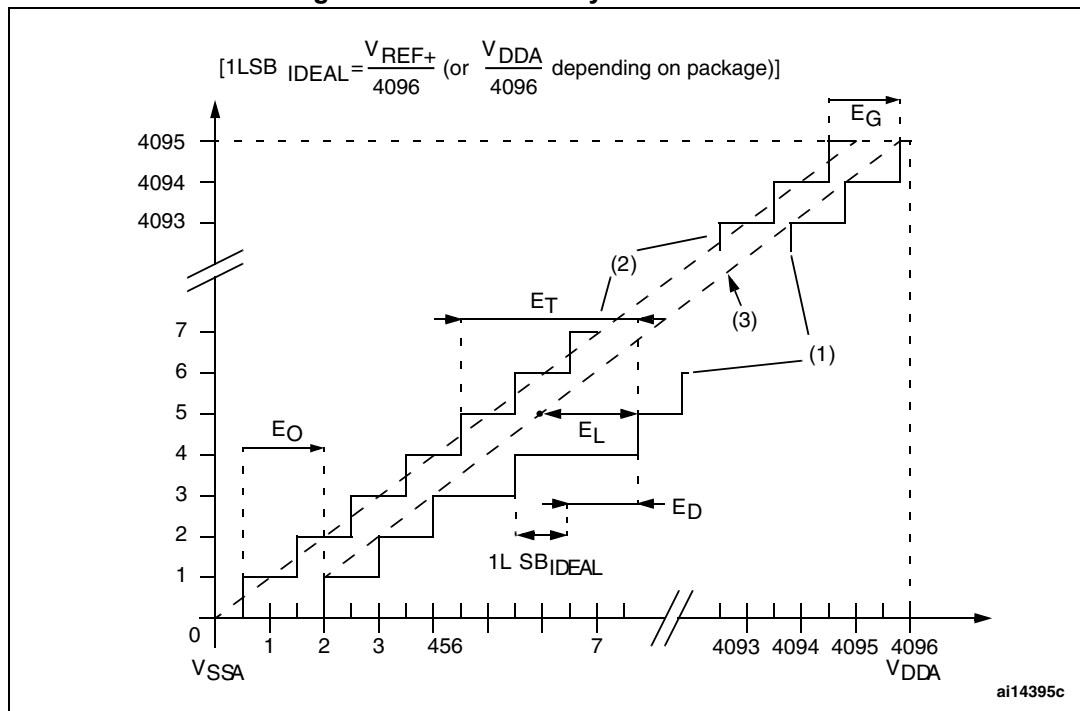
1. R_S = series protection resistor.
2. R_P = external pull-up resistor.
3. V_{DD_I2C} is the I²C bus power supply.

Table 60. SCL frequency ($f_{PCLK1} = 42$ MHz, $V_{DD} = V_{DD_I2C} = 3.3$ V)⁽¹⁾⁽²⁾

f_{SCL} (kHz)	I2C_CCR value
	$R_P = 4.7$ k Ω
400	0x8019
300	0x8021
200	0x8032
100	0x0096
50	0x012C
20	0x02EE

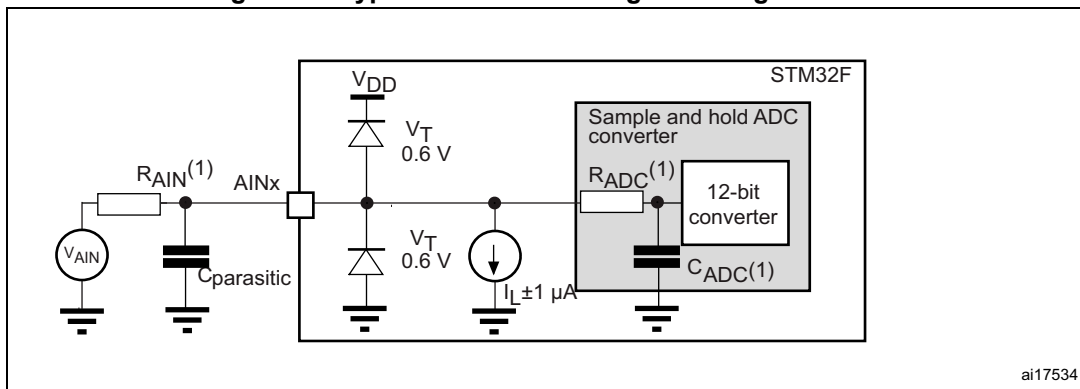
1. R_P = External pull-up resistance, f_{SCL} = I²C speed
2. For speeds around 200 kHz, the tolerance on the achieved speed is of $\pm 5\%$. For other speed ranges, the tolerance on the achieved speed is $\pm 2\%$. These variations depend on the accuracy of the external components used to design the application.

Figure 40. ADC accuracy characteristics



1. See also [Table 68](#).
2. Example of an actual transfer curve.
3. Ideal transfer curve.
4. End point correlation line.
5. E_T = Total Unadjusted Error: maximum deviation between the actual and the ideal transfer curves.
 E_O = Offset Error: deviation between the first actual transition and the first ideal one.
 E_G = Gain Error: deviation between the last ideal transition and the last actual one.
 E_D = Differential Linearity Error: maximum deviation between actual steps and the ideal one.
 E_L = Integral Linearity Error: maximum deviation between any actual transition and the end point correlation line.

Figure 41. Typical connection diagram using the ADC



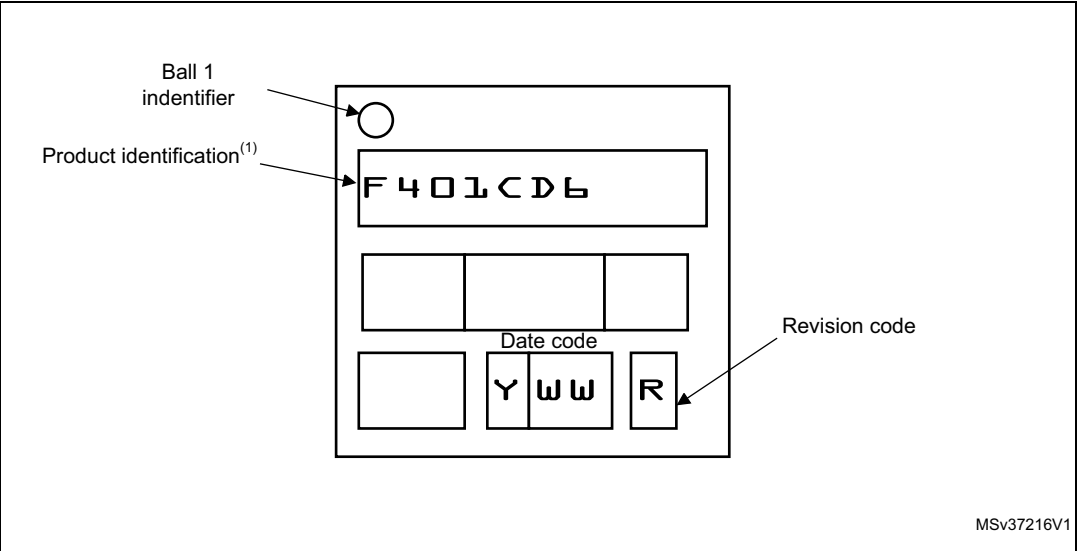
1. Refer to [Table 66](#) for the values of R_{AIN} , R_{ADC} and C_{ADC} .
2. $C_{parasitic}$ represents the capacitance of the PCB (dependent on soldering and PCB layout quality) plus the pad capacitance (roughly 5 pF). A high $C_{parasitic}$ value downgrades conversion accuracy. To remedy this, f_{ADC} should be reduced.

Table 80. WLCSP49 recommended PCB design rules (0.4 mm pitch)

Dimension	Recommended values
Pitch	0.4 mm
Dpad	260 µm max. (circular) 220 µm recommended
Dsm	300 µm min. (for 260 µm diameter pad)
PCB pad design	Non-solder mask defined via underbump allowed

Device marking

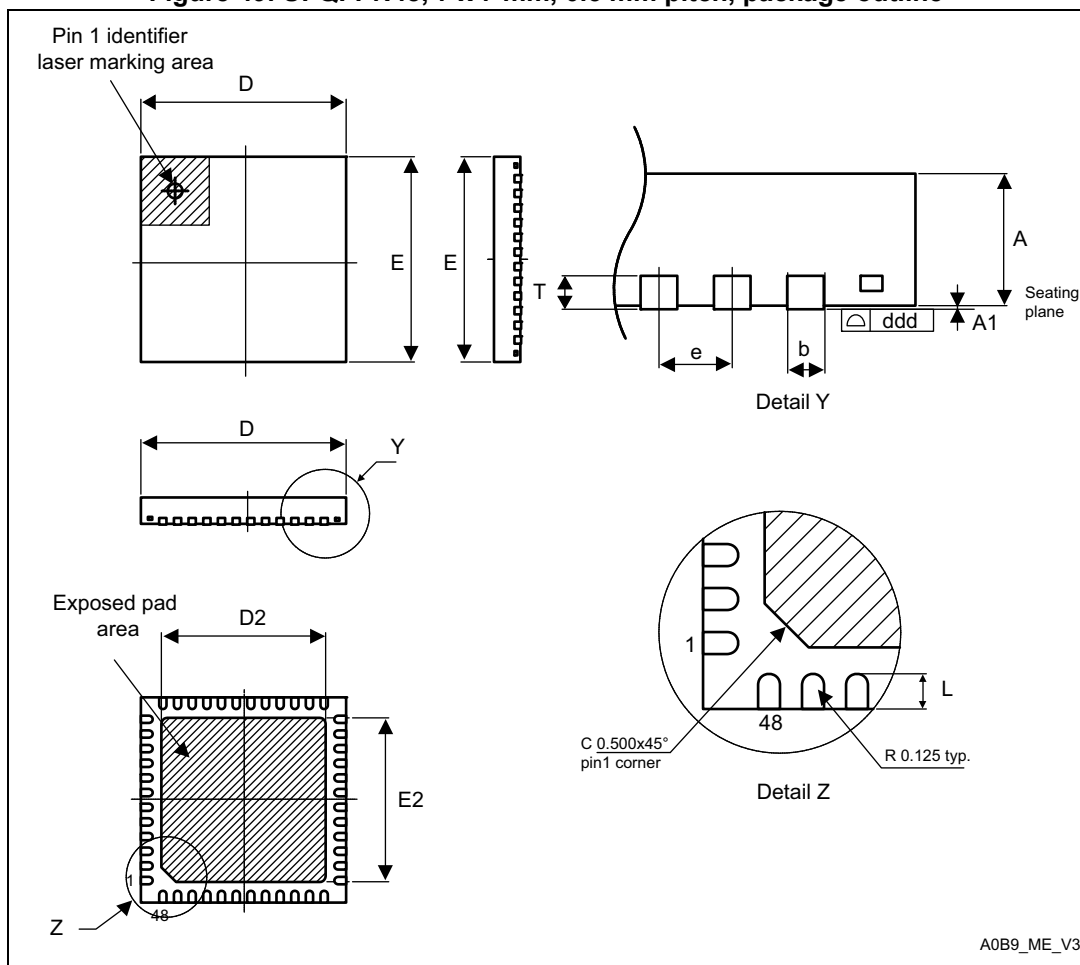
Figure 48. Example of WLCSP49 marking (top view)



1. Parts marked as “ES”, “E” or accompanied by an Engineering Sample notification letter, are not yet qualified and therefore not yet ready to be used in production and any consequences deriving from such usage will not be at ST charge. In no event, ST will be liable for any customer usage of these engineering samples in production. ST Quality has to be contacted prior to any decision to use these Engineering samples to run qualification activity.

7.1.2 UFQFPN48, 7 x 7 mm, 0.5 mm pitch package

Figure 49. UFQFPN48, 7 x 7 mm, 0.5 mm pitch, package outline



1. Drawing is not to scale.
2. All leads/pads should also be soldered to the PCB to improve the lead/pad solder joint life.
3. There is an exposed die pad on the underside of the UFQFPN package. It is recommended to connect and solder this back-side pad to PCB ground.

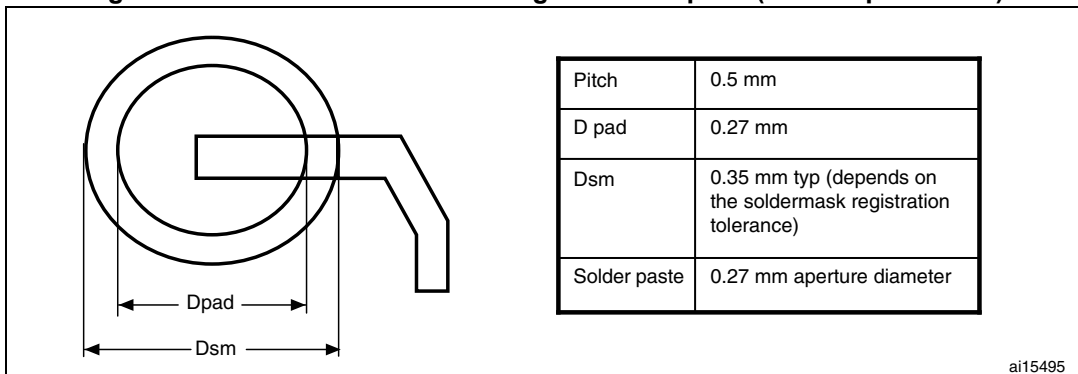
Table 81. UFQFPN48, 7 x 7 mm, 0.5 mm pitch, package mechanical data

Symbol	millimeters			inches ⁽¹⁾		
	Min.	Typ.	Max.	Min.	Typ.	Max.
A	0.500	0.550	0.600	0.0197	0.0217	0.0236
A1	0.000	0.020	0.050	0.0000	0.0008	0.0020
D	6.900	7.000	7.100	0.2717	0.2756	0.2795
E	6.900	7.000	7.100	0.2717	0.2756	0.2795
D2	5.500	5.600	5.700	0.2165	0.2205	0.2244
E2	5.500	5.600	5.700	0.2165	0.2205	0.2244
L	0.300	0.400	0.500	0.0118	0.0157	0.0197

Table 84. UFBGA100, 7 x 7 mm, 0.50 mm pitch, ultra fine pitch ball grid array package mechanical data (continued)

Symbol	millimeters			inches ⁽¹⁾		
	Min.	Typ.	Max.	Min.	Typ.	Max.
ddd	-	-	0.100	-	-	0.0039
eee	-	-	0.150	-	-	0.0059
fff	-	-	0.050	-	-	0.0020

1. Values in inches are converted from mm and rounded to 4 decimal digits.

Figure 59. Recommended PCB design rules for pads (0.5 mm-pitch BGA)

1. Non solder mask defined (NSMD) pads are recommended.
2. 4 to 6 mils solder paste screen printing process.